

**PATENT APPLICATION**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of

Docket No: Q79367

Kazuya UENISHI, et al.  
Appln. No.: 10/756,753

Allowed: December 12, 2005  
Group Art Unit: 2881

Confirmation No.: 1538

Examiner: Bernard E. SOUW

Filed: January 14, 2004

Issued: July 18, 2006

U.S. Patent No.: 7,078,687

For: THIN FILM ANALYZING METHOD

**SUBMISSION OF ART**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

For the possible benefit of anyone subsequently evaluating the scope and/or validity of the above-identified patent, it is requested that the document that is listed below (copy enclosed) be placed in the U.S. Patent and Trademark Office's file wrapper of the above-identified U.S. patent:

Japanese Patent No. 61-137041

Japanese Patent No. 2001-33405

Japanese Patent No. 2002-184828

The above-listed documents were recently cited in a communication from a Foreign Patent Office dated May 17, 2006.

The undersigned has not reviewed the teachings of the above-listed document in detail and thus makes no representations concerning the relevancy or materiality of the above-listed document.

SUBMISSION OF ART  
U.S. Patent Application No. 10/756,753  
U.S. Patent No. 7,078,687

Attorney Docket No.: Q79367

This is not an Information Disclosure Statement and no response from the U.S. Patent  
and Trademark Office is believed to be necessary, nor are any fees believed to be due.

Respectfully submitted,



Chid S. Iyer  
Registration No. 43,355

SUGHRUE MION, PLLC  
Telephone: (202) 293-7060  
Facsimile: (202) 293-7860

WASHINGTON OFFICE

23373

CUSTOMER NUMBER

Date: July 20, 2006